

In the name of god

# Implementation and test of embedded systems with ASIC

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CA2

## Part A

clock	Timing (slack)	area	Dynamic Power	Leakage Power
100MHz	8.58	296.352003	38.2185 uW	27.2254 pW
200MHz	3.58	296.352003	76.4370 uW	27.2254 pW
500MHz	0.58	296.352003	191.0925 uW	27.2254 pW
5GHz	-0.55	546.603609	6.2998 mW	92.0168 pW

4-a) When we increase clock frequency, it is harder for the design compiler to meet the slack as happens in the last case that it could not meet the timing constraint and there is timing violation.

4-b) Well, as long as the design compiler can make slack upper than zero, it would not change area and power.

4-c) First three cases slacks are met although in last one it violates it. The design compiler in this case done it best to reach the slack with cost of more area and power but it was not enough.

4-d) As mentioned above as long as slack won't violated power won't change at all but whenever it could not meet constrains add much complex cells that would increase power and area. In the first three cases dynamic power rose linearly cause has linear relation with clock frequency.

4-e) It was addressed before, that as long as design compiler can meet slack it wont changed design but if it could not uses complex cells that increase power consumption and area.

## Part B

delay	Timing (slack)	area	Dynamic Power	Leakage Power
1ns	3.42	296.352003	76.4370 uW	27.2254pW
0.2ns	3.58	296.352003	76.4370 uW	27.2254pW

The image shows two side-by-side screenshots of a timing analysis tool. The left screenshot shows the results for a delay of 1ns, and the right screenshot shows the results for a delay of 0.2ns. Both screenshots display a table of timing data for a circuit component named 'counter'.

Path Group: clk	Wire Load Model Mode: top
Path Type: max	
Des/Clust/Port	Wire Load Model Library
counter	Small sc7_ch018u11_base_rvt_tt_typ_max_1p80
Point	Incr Path
clock clk (rise edge)	2.50 2.50
clock network delay (ideal)	0.00 2.50
count_reg[1]/CK (DFFRQ_X2_A7TULL)	0.00 2.50 r
count_reg[1]/Q (DFFRQ_X2_A7TULL)	0.58 3.08 f
count[1] (out)	0.00 3.08 f
data arrival time	3.08
clock clk (rise edge)	7.50 7.50
clock network delay (ideal)	0.00 7.50
output external delay	-1.00 6.50
data required time	6.50
data required time	6.50
data arrival time	-3.08
slack (MET)	3.42

  

Path Group: clk	Wire Load Model Mode: top
Path Type: max	
Des/Clust/Port	Wire Load Model Library
counter	Small sc7_ch018u11_base_rvt_tt_typ_max_1p80
Point	Incr Path
clock clk (rise edge)	2.50 2.50
clock network delay (ideal)	0.00 2.50
count_reg[1]/CK (DFFRQ_X2_A7TULL)	0.00 2.50 r
count_reg[1]/Q (DFFRQ_X2_A7TULL)	0.56 3.06 r
U17/Y (NAND2_X2_A7TULL)	0.19 3.25 f
U14/Y (NOR2B_X2_A7TULL)	0.21 3.46 r
U13/Y (XOR2_X2_A7TULL)	0.22 3.68 r
count_reg[3]/D (DFFRQ_X2_A7TULL)	0.00 3.68 r
data arrival time	3.68
clock clk (rise edge)	7.50 7.50
clock network delay (ideal)	0.00 7.50
count_reg[3]/CK (DFFRQ_X2_A7TULL)	0.00 7.50 r
library setup time	-0.25 7.25
data required time	7.25
data required time	7.25
data arrival time	-3.68
slack (MET)	3.58

3-a) In this case I/O delays do not affect our design so much to make them negative. so, nothing changed. But if delay increases it might change area and power to achieve positive slack.

3-b) Nothing has changed cause there is no pressure on slack so design compiler didn't change the design.

3-c) There is no violation here.

3-d) There is no difference between two designs.

B_1.txt					B_2.txt				
C:\Users> moham > AppData > Local > Temp > 59ce8b2d-e5ba-4ff7-b7ee-c1baed73dbb6_my_log.zip.b66 > my_log > B_1.txt					C:\Users> moham > AppData > Local > Temp > 13caa0d-baee-4385-bf7b-c03d27660004_my_log.zip.004 > my_log > B_2.txt				
Attributes:					Attributes:				
277	n	-	noncombinational		282	n	-	noncombinational	
278	r	-	removable		283	r	-	removable	
279	u	-	contains unmapped logic		284	u	-	contains unmapped logic	
280					285				
281	Cell	Reference	Library	Area Attributes	286	Cell	Reference	Library	Area Attributes
282					287				
283	U3	INV_X2_A7TULL	sc7_ch018u11_base_rvt_tt_typ_max_1p80v	6.585600 d	288	U3	INV_X2_A7TULL	sc7_ch018u11_base_rvt_tt_typ_max_1p80v	6.585600 d
284	U4	INV_X2_A7TULL	sc7_ch018u11_base_rvt_tt_typ_max_1p80v	6.585600 d	289	U4	INV_X2_A7TULL	sc7_ch018u11_base_rvt_tt_typ_max_1p80v	6.585600 d
285	U5	INV_X2_A7TULL	sc7_ch018u11_base_rvt_tt_typ_max_1p80v	6.585600 d	290	U5	INV_X2_A7TULL	sc7_ch018u11_base_rvt_tt_typ_max_1p80v	6.585600 d
286	U6	INV_X2_A7TULL	sc7_ch018u11_base_rvt_tt_typ_max_1p80v	6.585600 d	291	U6	INV_X2_A7TULL	sc7_ch018u11_base_rvt_tt_typ_max_1p80v	6.585600 d
287	U13	XOR2_X2_A7TULL	sc7_ch018u11_base_rvt_tt_typ_max_1p80v	19.756800	292	U13	XOR2_X2_A7TULL	sc7_ch018u11_base_rvt_tt_typ_max_1p80v	19.756800
288	U14	NOR2B_X2_A7TULL	sc7_ch018u11_base_rvt_tt_typ_max_1p80v	10.976000	293	U14	NOR2B_X2_A7TULL	sc7_ch018u11_base_rvt_tt_typ_max_1p80v	10.976000
289	U15	XNOR2_X2_A7TULL	sc7_ch018u11_base_rvt_tt_typ_max_1p80v	19.756800	294	U15	XNOR2_X2_A7TULL	sc7_ch018u11_base_rvt_tt_typ_max_1p80v	19.756800
290	U16	XNOR2_X2_A7TULL	sc7_ch018u11_base_rvt_tt_typ_max_1p80v	19.756800	295	U16	XNOR2_X2_A7TULL	sc7_ch018u11_base_rvt_tt_typ_max_1p80v	19.756800
291	U17	NAND2_X2_A7TULL	sc7_ch018u11_base_rvt_tt_typ_max_1p80v	8.780800	296	U17	NAND2_X2_A7TULL	sc7_ch018u11_base_rvt_tt_typ_max_1p80v	8.780800
292	U18	INV_X2_A7TULL	sc7_ch018u11_base_rvt_tt_typ_max_1p80v	6.585600	297	U18	INV_X2_A7TULL	sc7_ch018u11_base_rvt_tt_typ_max_1p80v	6.585600
293	count_reg[0]	DFFRQ_X2_A7TULL	sc7_ch018u11_base_rvt_tt_typ_max_1p80v	46.099201 n	298	count_reg[0]	DFFRQ_X2_A7TULL	sc7_ch018u11_base_rvt_tt_typ_max_1p80v	46.099201 n
294	count_reg[1]	DFFRQ_X2_A7TULL	sc7_ch018u11_base_rvt_tt_typ_max_1p80v	46.099201 n	299	count_reg[1]	DFFRQ_X2_A7TULL	sc7_ch018u11_base_rvt_tt_typ_max_1p80v	46.099201 n
295	count_reg[2]	DFFRQ_X2_A7TULL	sc7_ch018u11_base_rvt_tt_typ_max_1p80v	46.099201 n	300	count_reg[2]	DFFRQ_X2_A7TULL	sc7_ch018u11_base_rvt_tt_typ_max_1p80v	46.099201 n
296	count_reg[3]	DFFRQ_X2_A7TULL	sc7_ch018u11_base_rvt_tt_typ_max_1p80v	46.099201 n	301	count_reg[3]	DFFRQ_X2_A7TULL	sc7_ch018u11_base_rvt_tt_typ_max_1p80v	46.099201 n
297					302				
298	Total 14 cells			296.352003	303	Total 14 cells			296.352003
299	design_vision> Current design is 'counter'.				304	design_vision> Current design is 'counter'.			
300					305				

## Part C

	Timing (slack)	area	Dynamic Power	Leakage Power
100%	3.58	296.352003	76.4370 uW	27.2254 pW
80%	3.58	296.352003	76.4370 uW	27.2254 pW

3-a) For this case our design is too small. so basically, design compiler done its best and cannot optimize it more and make it smaller. So, there are no changes.

3-b) As addressed in last part in this case there is no trade-off. However, in larger design it might be possible to affect timing and make it worse.

3-c) If the design was larger, it might be!

3-d) As the illustration below states there are no changes.

Cell	Reference	Library	Area	Attributes
U3	INV_X2_A7TULL	sc7_ch018u11_base_rvt_tt_ttyp_max_1p80v	6.585600	d
U4	INV_X2_A7TULL	sc7_ch018u11_base_rvt_tt_ttyp_max_1p80v	6.585600	d
U5	INV_X2_A7TULL	sc7_ch018u11_base_rvt_tt_ttyp_max_1p80v	6.585600	d
U6	INV_X2_A7TULL	sc7_ch018u11_base_rvt_tt_ttyp_max_1p80v	6.585600	d
U13	XOR2_X2_A7TULL	sc7_ch018u11_base_rvt_tt_ttyp_max_1p80v	19.756800	
U14	NOR2B_X2_A7TULL	sc7_ch018u11_base_rvt_tt_ttyp_max_1p80v	10.976000	
U15	XNOR2_X2_A7TULL	sc7_ch018u11_base_rvt_tt_ttyp_max_1p80v	19.756800	
U16	XNOR2_X2_A7TULL	sc7_ch018u11_base_rvt_tt_ttyp_max_1p80v	19.756800	
U17	NAND2_X2_A7TULL	sc7_ch018u11_base_rvt_tt_ttyp_max_1p80v	8.780800	
U18	INV_X2_A7TULL	sc7_ch018u11_base_rvt_tt_ttyp_max_1p80v	6.585600	
count_reg[0]	DFFRQ_X2_A7TULL	sc7_ch018u11_base_rvt_tt_ttyp_max_1p80v	46.099201	n
count_reg[1]	DFFRQ_X2_A7TULL	sc7_ch018u11_base_rvt_tt_ttyp_max_1p80v	46.099201	n
count_reg[2]	DFFRQ_X2_A7TULL	sc7_ch018u11_base_rvt_tt_ttyp_max_1p80v	46.099201	n
count_reg[3]	DFFRQ_X2_A7TULL	sc7_ch018u11_base_rvt_tt_ttyp_max_1p80v	46.099201	n
Total 14 cells			296.352003	
design_vision> Current design is 'counter'.				